Applicant(s)/Patent Under Application/Control No. Reexamination 10/729,865 CHEN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2824 VanThu Nguyen **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,380,636 B1 04-2002 Tatsukawa et al. 257/390 Α US-6,147,911 A 11-2000 Takeuchi et al. 365/185.28 В US-С US-D US-Ε US-F US-G US-Н US-US-J USκ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Country Code-Number-Kind Code Classification MM-YYYY Ν 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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